## Notice of References Cited

Application/Control No. 10/789,497	Applicant(s)/Patent Under Reexamination KUROHATA ET AL.		
Examiner	Art Unit		
Allen H. Nguyen	2625	Page 1 of 1	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0107854	06-2004	Nakatani et al.	101/484
*	В	US-2002/0054008	05-2002	Aikawa, Masafumi	345/100
*	С	US-2003/0016391	01-2003	Tamura, Noboru	358/1.16
*	D	US-2002/0051207	05-2002	Ohkubo et al.	358/1.18
*	Е	US-6,404,994	06-2002	Kawai et al.	399/6
*	F	US-6,160,922	12-2000	Hayashi, Kouji	382/274
*	G	US-6,632,035	10-2003	Kawamoto, Hirokazu	400/61
*	Н	US-6,924,826	08-2005	Nakagiri et al.	715/700
*	ŀ	US-2002/0090223	07-2002	Ohtani, Masaki	399/82
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				,	
	0				·	·
	Р					
	Q	٥	,			
	R		,		·	
	S					
	Т					

## **NON-PATENT DOCUMENTS**

	NON-PATENT DOCUMENTS		
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
٠	V		
	w		
	x		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.